

AMENDMENTS TO THE CLAIMS

The following claims are presented for examination:

1. (cancelled)
2. (currently amended) The integrated circuit of claim ~~1~~³ wherein said first device comprises an n-type metal-oxide semiconductor field-effect transistor.
3. (currently amended) ~~The integrated circuit of claim 1~~ An integrated circuit comprising:
a first device comprising a first lead, a second lead, and a third lead, wherein said third lead of said first device is electrically connected to ground; and
a second device comprising a first lead, a second lead, and a third lead, wherein said third lead of said second device is electrically connected to ground, and wherein said first lead of said second device is electrically connected to said first lead of said first device;
wherein the effective threshold voltage of said first device is more susceptible to be lowered by ionizing radiation than is the effective threshold voltage of said second device; and
wherein said first device comprises a field oxide that has been implanted with a material that traps positive charge when said first device is exposed to ionizing radiation and said second device has not been implanted with said material.
4. (currently amended) The integrated circuit of claim ~~1~~³ wherein said integrated circuit further comprises a microprocessor that comprises a control sequencer coupled to an arithmetic logic unit.
5. (currently amended) The integrated circuit of claim ~~1~~³ wherein said integrated circuit further comprises an arrangement of memory cells operatively coupled to an address decoder.
6. (cancelled)
7. (currently amended) The integrated circuit of claim ~~1~~³ wherein said first device shorts power to ground when said device has been exposed to ionizing radiation.

8-21. (cancelled)

22. (previously presented) An integrated circuit comprising:

a safeguard device comprising a first lead, a second lead, and a third lead, wherein said third lead of said first device is electrically connected to ground; and

a utile device comprising a first lead, a second lead, and a third lead, wherein said third lead of said second device is electrically connected to ground, and wherein said first lead of said second device is electrically connected to said first lead of said first device;

wherein upon exposure to a sufficient amount of ionizing radiation, said safeguard device turns on before said utile device, and affects operation of said utile device.

23. (previously presented) The integrated circuit of claim 22 wherein said safeguard device is connected between power and ground, so that, when said safeguard device turns on, it shorts power to ground.

24. (previously presented) The integrated circuit of claim 22 wherein said safeguard device is connected between a signal lead and ground, so that, when said safeguard device turns on, it shorts said signal lead to ground.

25. (previously presented) The integrated circuit of claim 22 said safeguard device comprises an *n*-type metal-oxide semiconductor field-effect transistor.